

Abstract Submitted  
for the MAR13 Meeting of  
The American Physical Society

**Theoretical Study of the Properties of the Type II Clathrates  $A_xB_{136}$  ( $A$ =alkali atom;  $B$ =Si, Ge, Sn  $0 \leq x \leq 24$ )** DONG XUE, CRAIG HIGGINS, CHARLEY MYLES<sup>1</sup>, Department of Physics, Texas Tech University — Type II clathrate semiconductors have cage-like lattices in which Group IV atoms are tetrahedrally-coordinated and  $sp^3$  covalently bonded. The cages can contain “guest” atoms; usually alkali or alkaline earth atoms. These materials are of interest because of their thermoelectric properties. Motivated by recent experimental and theoretical interest [1,2] in the  $x$  dependence of properties of the Si and Ge-based Type II clathrate materials  $A_xSi_{136}$  and  $A_xGe_{136}$  ( $A$  = alkali atom) we are carrying out a systematic theoretical study of the properties of the Type II clathrate systems  $A_xB_{136}$  ( $A$  = alkali atom;  $B$  = Si, Ge, Sn). Recent powder X-ray diffraction experiments have found the very interesting result that in  $Na_xSi_{136}$ , for increasing  $x$  in the range  $0 \leq x \leq 8$  a lattice contraction occurs and that as  $x$  is increased further ( $8 \leq x \leq 24$ ), a contrasting lattice expansion results. These observations have motivated us to study the behavior of the lattice constant and other properties as a function of guest concentration in several Type II clathrates. We present results of a density functional based study of the properties of  $A_xB_{136}$  as a function of  $x$ . Results are discussed for the  $x$  dependence of the lattice constant and for other structural and electronic properties of these materials. [1] S. Stefanoski and G. Nolas, Cryst. Growth Des. 2011, dx.doi.org/10.1021/cg200756r [2] M. Beekman, E. Nenghabi, K. Biswas, C. Myles, M. Baitinger, Y. Grin, G.S. Nolas, Inorg. Chem. 49 2010, DOI: 10.1021/ic1005049

<sup>1</sup>Dr. Charley W. Myles is the professor of Physics Department at Texas Tech University.

Dong Xue  
Department of Physics, Texas Tech University

Date submitted: 18 Nov 2012

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